System and Method for Imaging a Surface Defect on an Object

Abstract

A system and a method for imaging a surface defect on an object are provided. The system includes an actuator, a sensor assembly connected to the actuator, and a processor configured to control the actuator and the sensor assembly. The sensor assembly includes at least one sensor configured to capture at least one image of the object. The processor is configured to control the actuator and the sensor assembly to identify a region of interest associated with the surface defect using an image of the object and to repeatedly identify at least one subsequent region of interest associated with the surface defect using at least a preceding region of interest such that the surface defect is identified according to a predetermined criterion.

Fig. 3